

<b>Notice of References Cited</b>	Application/Control No. 10/507,493		Applicant(s)/Patent Under Reexamination EDWIN ET AL.	
	Examiner Samir M. Shah		Art Unit 2856	Page 1 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,623,107	04-1997	Patterson et al.	73/865.8
*	B	US-4,903,413	02-1990	Bellwood, Philip R.	33/551
*	C	US-4,084,324	04-1978	Whitehouse, David John	33/504
*	D	US-5,535,143	07-1996	Face, Allen	702/165
*	E	US-4,240,206	12-1980	Baresh et al.	33/558
*	F	US-5,337,485	08-1994	Chien, An Y.	33/550
*	G	US-1,845,199	02-1932	SCHNUCK CARL F	33/501.07
*	H	US-5,088,207	02-1992	Betsill et al.	33/555.3
*	I	US-6,782,631 B1	08-2004	Face, III, S. Allen	33/533
*	J	US-6,820,347 B2	11-2004	Mellander, William E.	33/555.1
*	K	US-3,861,047	01-1975	Dietrich, Otto E.	33/532
*	L	US-3,695,539	10-1972	Lindstaedt, Horst Karl	242/559
*	M	US-4,708,300	11-1987	Goetz, Willi	242/551

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 63288708 A	11-1988	Japan	UTSUNOMIYA et al.	B28B 03/12
	O	JP 60073413 A	04-1985	Japan	SUDO et al.	G01B 21/30
	P	WO 9118260 A1	11-1991	World Intellect	SCHMID et al.	G01B 17/00
	Q	EP 507553 A2	10-1992	European Patent	BAGDAL, KARL THOMAS	G01B 11/24
	R	WO 9508095 A1	03-1995	World Intellect	MERIN et al.	G01B 21/20
	S	WO 9936616 A1	07-1999	World Intellect	KOIVUKUNNAS et al.	D21G 01/00
	T	WO 9967758 A1	12-1999	World Intellect	DAUMER, MARTIN	G08B 29/18

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Frank, Ernest, "Electrical Measurement and Analysis", 1959, McGraw Hill Book Company, Inc., pages 132-157
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/507,493		Applicant(s)/Patent Under Reexamination EDWIN ET AL.	
	Examiner Samir M. Shah		Art Unit 2856	Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,863,335	09-1989	Herigstad et al.	414/495
*	B	US-4,948,060	08-1990	Kurz et al.	242/552
*	C	US-5,067,871	11-1991	Hilber, Walter	414/807
*	D	US-5,076,751	12-1991	Kafka, Alfred J.	414/282
*	E	US-5,388,955	02-1995	Schroder, Niels	414/279
*	F	US-6,155,516	12-2000	Lehrieder et al.	242/559.3
*	G	US-6,685,130	02-2004	Stauber et al.	242/533.8
*	H	US-5,353,356	10-1994	Waugh et al.	382/143
*	I	US-6,287,217	09-2001	Sullivan et al.	473/374
*	J	US-6,288,664	09-2001	Swanson, Eric J.	341/155
*	K	US-6,556,957	04-2003	Daumer, Martin	702/193
*	L	US-6,558,913	05-2003	Bertina et al.	435/13
*	M	US-2002/0068270 A1	06-2002	Crawford, J. Fred	435/4

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/507,493	Applicant(s)/Patent Under Reexamination EDWIN ET AL.	
	Examiner Samir M. Shah	Art Unit 2856	Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0087389 A1	07-2002	Sklarz et al.	705/10
*	B	US-6,568,096 B1	05-2003	Svitkin et al.	33/550
*	C	US-4,050,293	09-1977	Shimomura et al.	73/105
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.